

Notice of References Cited

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Applicant(s)/Patent Under

Reexamination

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Examiner

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0033524	03-2002	TOYOSAWA et al.	257/678
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N	JP-05-323355	12-1993	Japan	Muramatsu Eiji	H01L 21/60
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NON-PATENT DOCUMENTS

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